

## **Task Force On Faulted Circuit Indicators**

### **Minutes from Winter meeting in New York on Jan 29, 2002**

1. The Task Force met on Tuesday, January 29<sup>th</sup>, 2002 with 8 present. Attendance list updated.
2. The single phase application guide has been issued as IEEE Std. 1216-2000.
3. Request for Three Phase Guide PAR has been submitted to IEEE by John Banting.
4. Dave Donovan to be the ICC liaison, and Harry Hayes will act as back-up.
5. Copies of P495, Guide for Testing Faulted Circuit Indicators – Draft 1, handed out for review by group. The Task Force agreed to work on both the “Test Guide” and the “Three Phase Application Guide” concurrently.
6. Draft 2 of Three Phase Guide handed out and discussed. Sections 1 through 4 reviewed. Task Force members are to review document for discussion at next meeting in New York.
7. Discussion of three-phase application guide draft.
  - Definition of three phase devices
  - Application on Parallel, Wye, and Delta circuits
  - Coordination with current limiting fuses
  - Proximity effect
  - Inrush characteristics
  - Expected useful life (Test Guide issue? Batteries?)
  - Maintenance practices
  - Auto reclose
  - Capacitor discharge effects
  - Backfeed current
  - Single phase protection on three phase systems
8. Action Items
  - Fran Angerer – Review Definitions for consistency between both documents and IEEE definitions.
  - John Banting – Update and distribute updated drafts.

- Dave Donovan / Harry Hayes – supply list of interested ICC members for inclusion in meeting minutes.
- John Banting / Dave Donovan – Coordinate efforts of ICC and Distribution committee regarding FCI Standards.
- All – Review Draft 3 of Three Phase Guide and Draft 1 of P495 Test Guide and provide input to John Banting.
- All – Review Burke and Donovan information for three phase systems.

9. Meeting adjourned at 11:30 am.

Submitted by John F. Banting, P.E.